Application/Control No. Applicant(s)/Patent Under Reexamination 10/067,350 FUJII ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2179 Ba Huynh **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY 379/202.01 US-2002/0071540 06-2002 Dworkin, David S. Α В US-С US-US-D Ε US-F US-G US-US-Н US-1 J US-Κ US-L US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) ν W

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